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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney Docket No. 15670-0029US1	Application No. 10/558,842	
Information Disclosure Statement by Applicant		Applicant Chung-Kuan Cheng, et al		
(Use several sheet	ts if necessary)	Filing Date January 18, 2007	Group Art Unit 2825	/N.N./

	U.S. Patent Documents						
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
/N.N./	1	2009/0132975	5/21/2009	Cheng et al.			
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Examiner Signature	Date Considered
/Nha Nguyen/	03/23/2010
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